

FAPG150D Fully automatic double side prober

Focus on DIODE, TVS, MOSFET, IGBT wafer level device probing. PEGASUS FAPG150D fully automatic double side probe provide you, auto wafer pick up, wafer level adjustment and wafer map scan. Whole wafer holder design provide you stable and fast testing, and also control perfect probe mark for all of your products.

Features

- For double side wafer application
- Windows OS, easy to operation
- Recipe editable
- Wafer level adjustment
- Modularization design, easy to keep
- High precision motor, low noise
- Two cassette design
- TL/RS232 interface integrable for all the tester
- High performance probing speed and tip mark great
- control
- Customize available
- Support 4 or 6 inch wafer holder
- Simple operation platform and joystick design
- Wafer mapping creation and editing



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Specifications

X/Y axis

- Architecture: High-precision circulating ball screw
- Travel: 285mm × 250mm
- Resolution: 0.5 μm
- Accuracy: $\leq \pm 7 \mu\text{m} / 203\text{mm}$
- Repeatability: $\leq \pm 4 \mu\text{m} / 203\text{mm}$

Clip arm

- Stroke : 20mm
- Resolution : 1μm
- Accuracy : $\leq \pm 2\mu\text{m}$
- Repeatability : $\leq \pm 4\mu\text{m}$

Wafer holder

- Material : Peek
- Size : 6" or 4" available

Stage

- Inker : 1set

Throughput

Test Time (ms)	Index Step(μm)				
	300	500	1000	2000	
Chuck Lift (μm)	300	42	47	56	70
	500	52	57	66	80
	800	62	67	76	90
	1000	68	74	83	97

Microscope

- Digital Microscope
- LED light inside
- Magnification: X20 ~ X90

Dimension

- 1020(D) × 1360(W) × 1465(H) mm
(exclude LCD monitor and signal tower)

Weight

- 550Kg((Excludes tester))

Vacuum

- 4-6Kgf/cm²

Air Pressure

- 0.5MPa